

**Amendments to the Claims:**

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This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently Amended) A method for estimating repair accuracy ~~of a mask shop~~ comprising the steps of:

providing a mask having a light-shielding layer with a pattern of a plurality of lines, each of which has a defect;

~~using the mask shop to repair~~ repairing the defects, whereby contaminated areas are formed in the vicinity of areas where the defects are repaired;

measuring first light intensities of the contaminated areas, and second and third light intensities of two sides of the contaminated areas; and

calculating ratios of means of the second and third light intensities to the first light intensities for estimating the repair accuracy.

2. (Currently Amended) The method as claimed in claim 1 further comprising the step of:

calculating a mean and  $3[\delta]\sigma$  value of the ratios.

3. (Original) The method as claimed in claim 1 wherein the lines comprise a plurality of vertical and horizontal lines.

4. (Original) The method as claimed in claim 3 wherein widths of the

lines range from  $0.5\mu\text{m}$  to  $2\mu\text{m}$ .

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5. (Original) The method as claimed in claim 1 wherein widths of the defects along the lines range from  $0.3\mu\text{m}$  to  $1.5\mu\text{m}$ .

6. (Original) The method as claimed in claim 1 wherein the defects are indentations on the lines.

7. (Original) The method as claimed in claim 1 wherein the light-shielding layer is a chrome layer.